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Si doped n-type GaAs/AlGaAs HEIWIP terahertz detector

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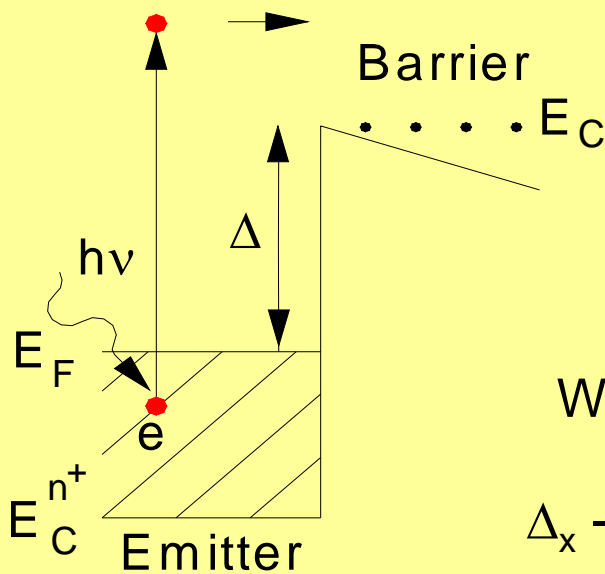
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HEterojunction Interfacial Workfunction Internal Photoemission Detector

- Detection mechanism in HEIWIP



Work function $\Delta = \Delta_x + \Delta_d$

Δ_x - Band offset between emitter and barrier

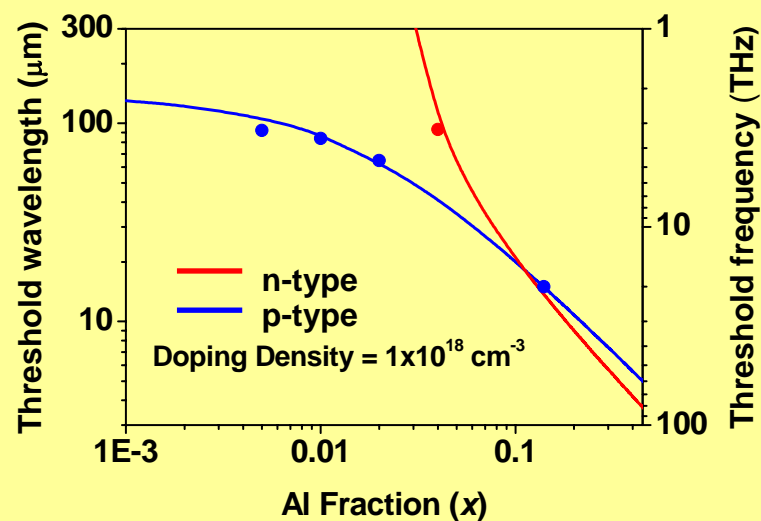
$$\Delta_d = E_{\text{narrow}} - E_F$$

- Threshold freq (wavelength) tailorable over a wide range
- Normal incidence response
- Broadband response easily achieved
- High quantum efficiency
- Lower dark current [APL **78**, 224 (2001)]

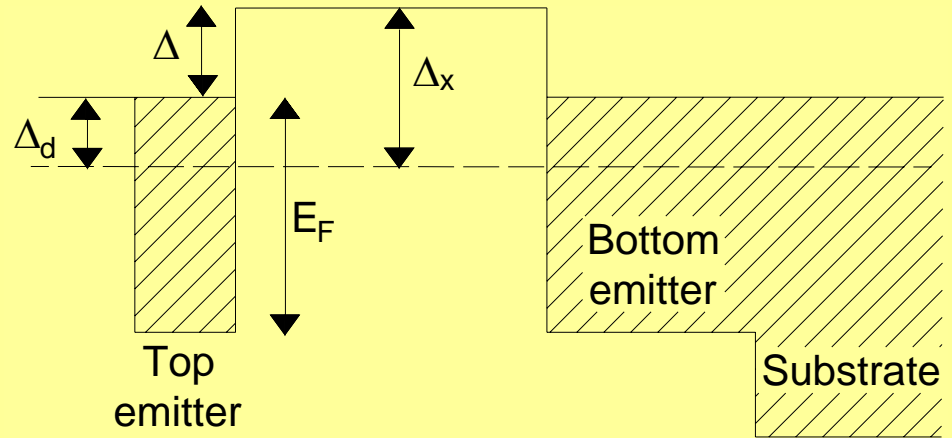
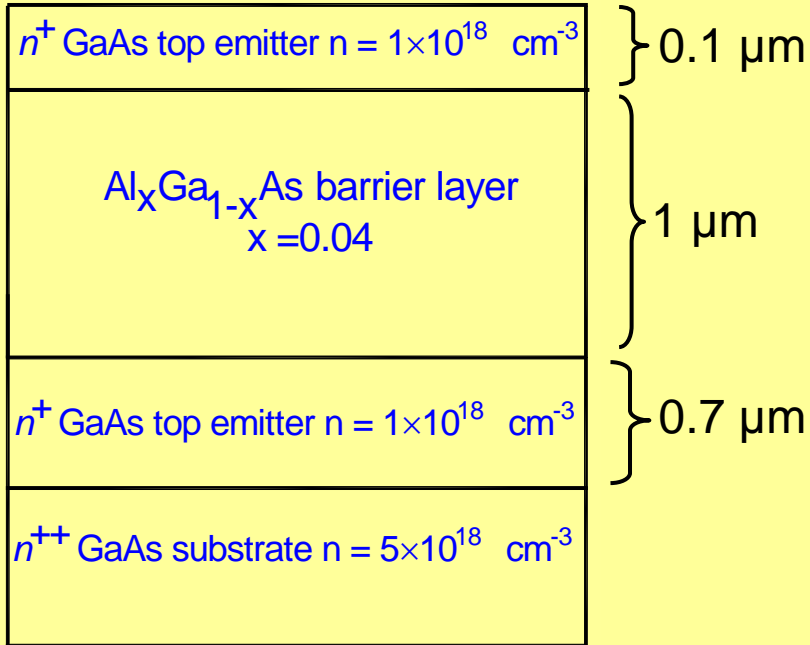
- Reported results are limited to p – type HEIWIP
- Easy to control the Fermi level and threshold frequency in p - type
- However, below 3 THz is difficult due to very low Al fraction (0.005) requirement¹

Alternatives:

- doped AlGaAs emitter and undoped GaAs barrier: obtained 2.3 THz threshold²
- n-type HEIWIP detectors



1. Matsik et.al., *Appl. Phys. Lett.*, 82, (2003)
2. Rinzan et. al., *Appl. Phys. Lett.*, 86, (2005)



$$\Delta_x = 32 \text{ meV}$$

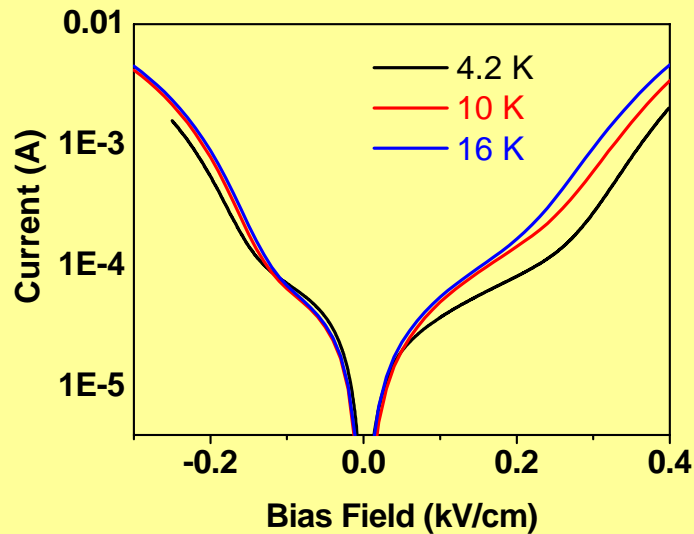
$$E_F = 56 \text{ meV},$$

$$E_{\text{narrow}} \sim 36 \text{ meV},$$

$$\Delta_d \sim -20 \text{ meV}$$

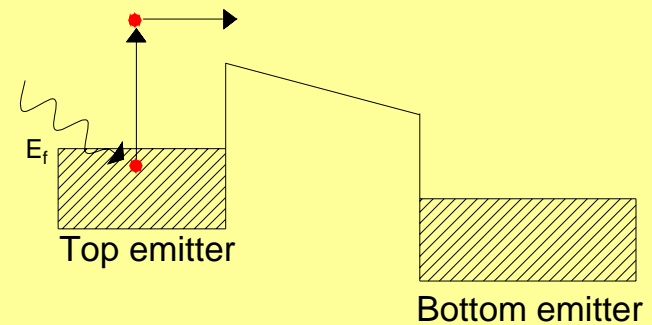
$$\Delta \sim 12 \text{ meV}$$

- Dark current measurements

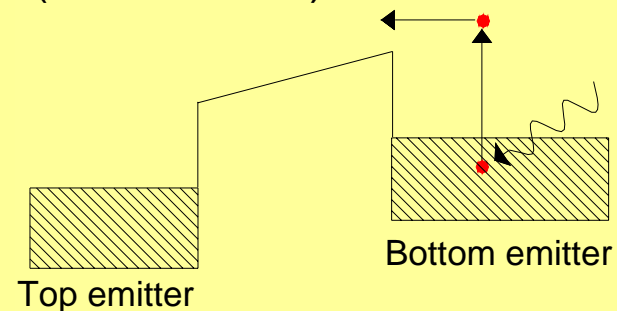


- Photoresponse measurements

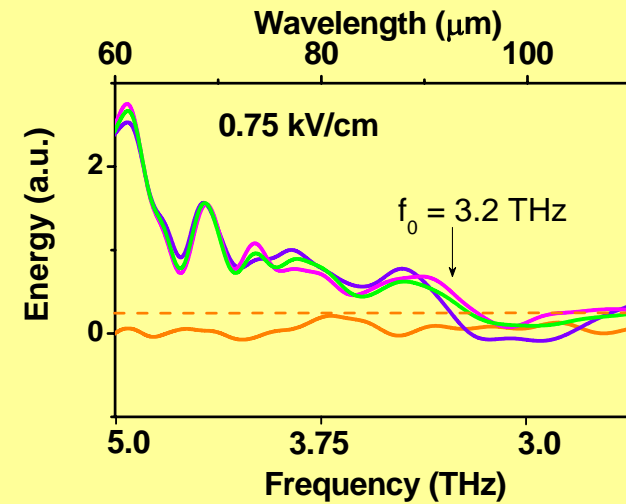
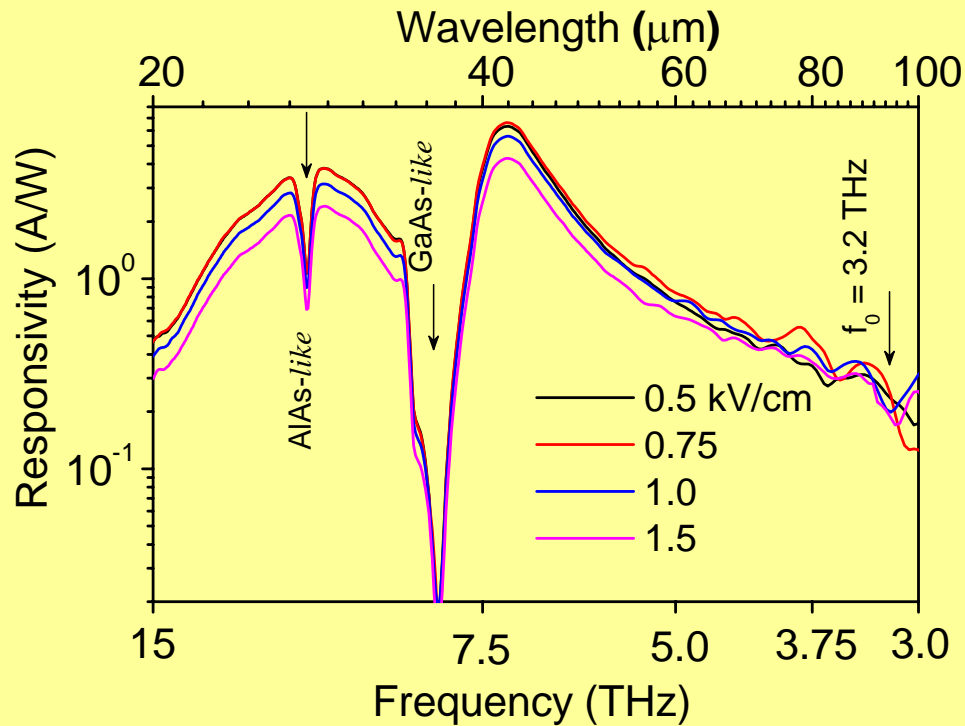
- (a) Emission from top emitter (reverse bias)



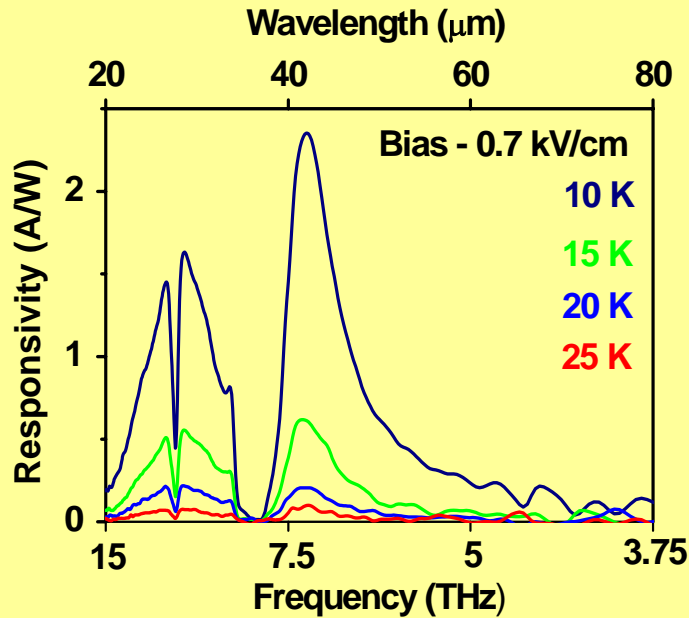
- (b) Emission from bottom emitter (forward bias)



- Forward bias (Photoemission from bottom emitter)



- Spectra taken at 6 K
- Used Si composite bolometer to calibrate raw spectra
- Threshold frequency (f_0) – 3.2 THz (93 μm), $R_{\text{peak}} = 6.4$ A/W at 7.1 THz at 0.7 kV/cm

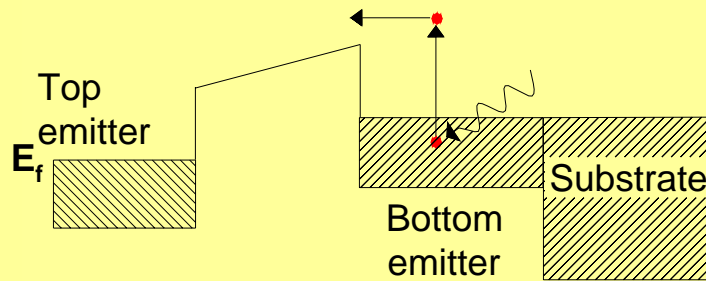


- Spectral response up to 25 K

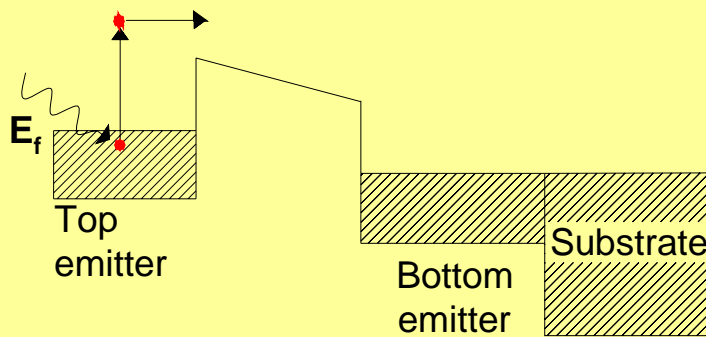
At 6 K

Bias (kV/cm)	R_{Peak} (A/W)	η_{Peak} (%)	$D^*_{\text{Peak}} \times 10^{10}$ (Jones)
0.2	3.0	8.9	5.1
0.5	6.1	18.2	4.4
0.7	6.4	18.9	3.4
1.0	5.5	16.4	1.7
1.5	4.1	12.3	1.5

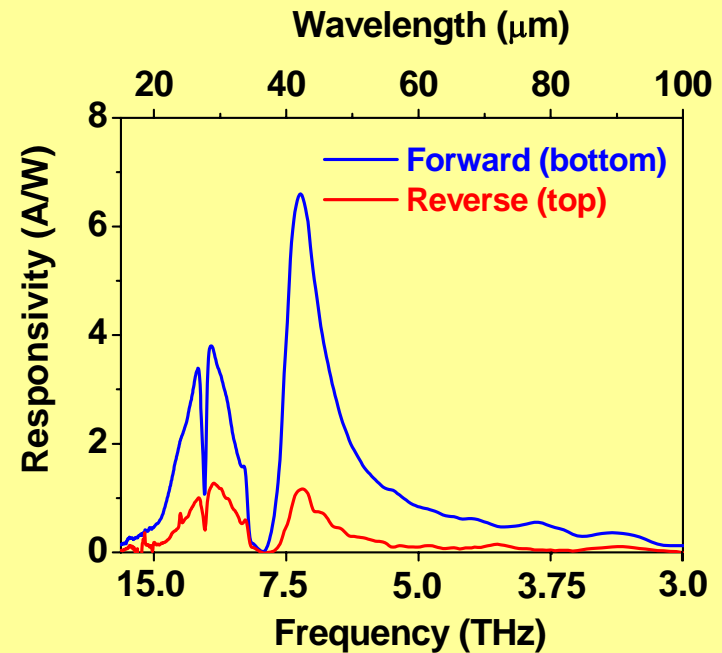
- Forward Bias



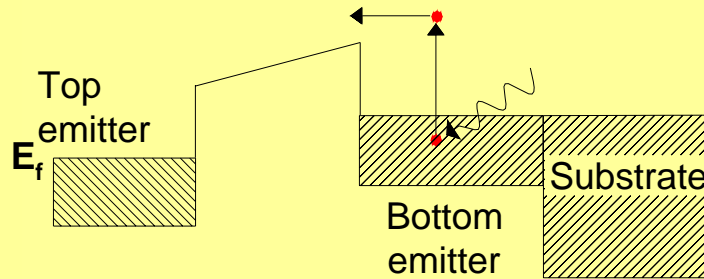
- Reverse Bias



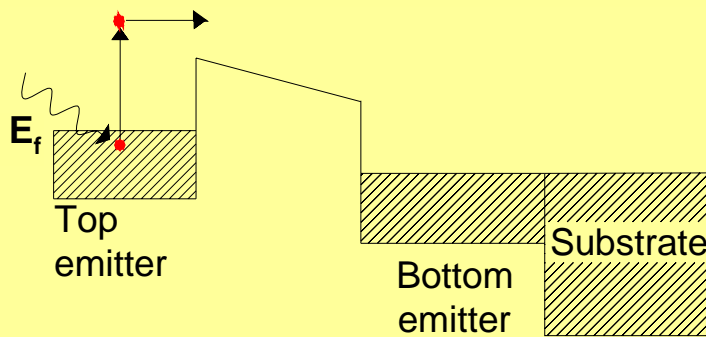
Responsivity from top and bottom emitters



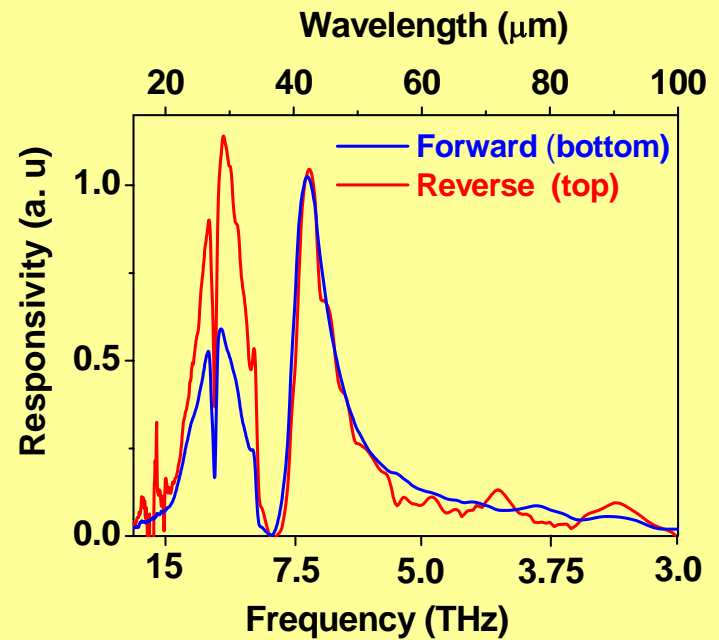
- Forward Bias



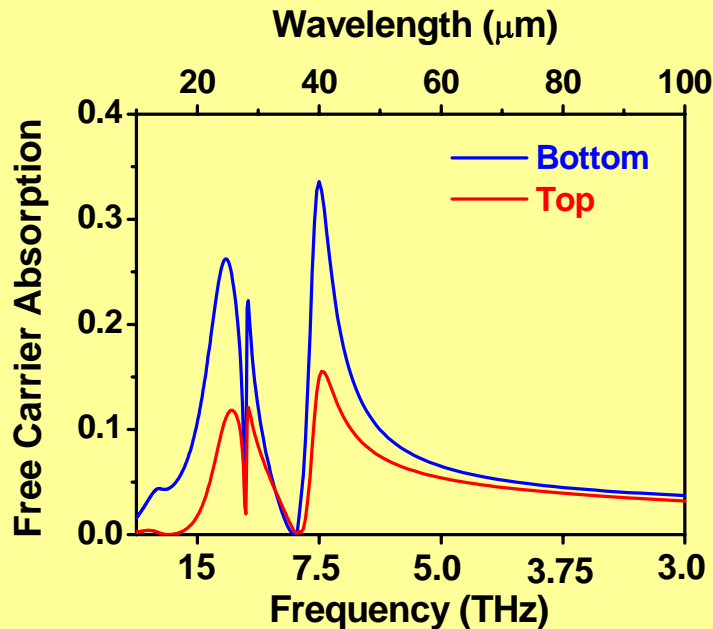
- Reverse Bias



Responsivity from top and bottom emitters



Calculated photo absorption in top and bottom emitters



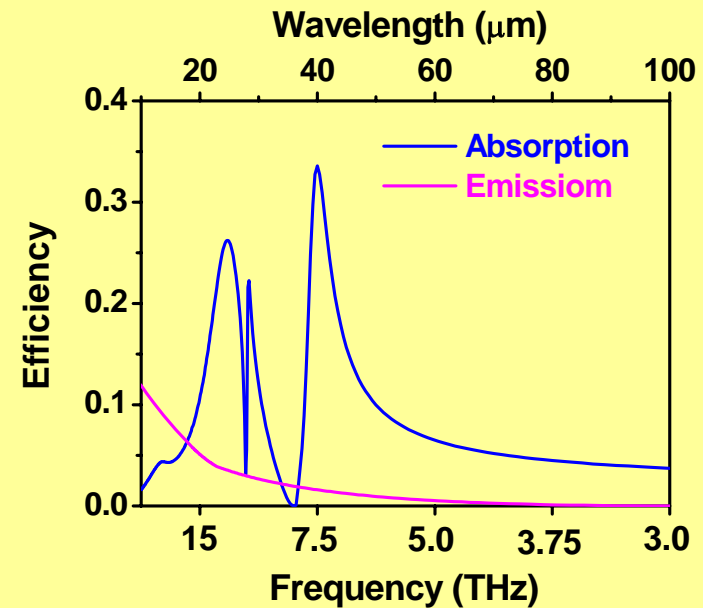
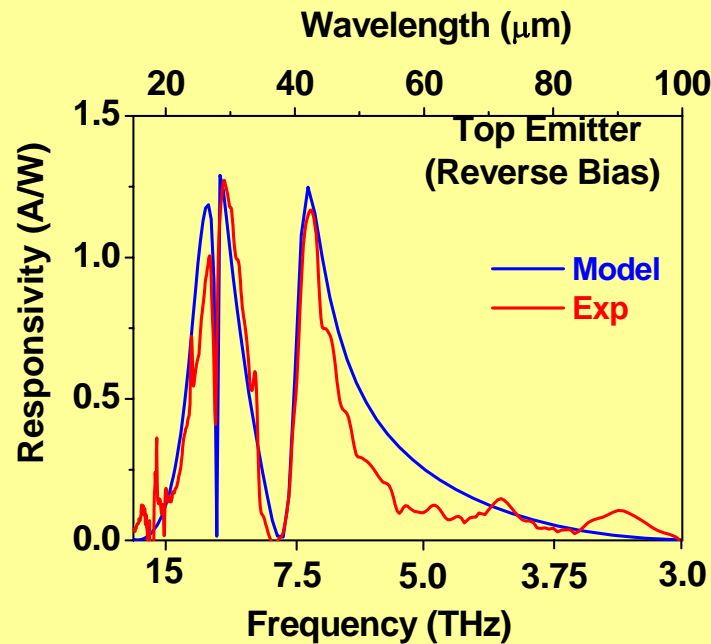
Absorption probability

$$\eta_a = 2 \tilde{I} \frac{\omega}{c} \text{Im}\{\varepsilon\} W$$

- The maximum absorption around 7.5 THz in both top and bottom emitters

Photoemission

- Used escape cone model for photo emission¹
- Assumed $L_p = 20$ nm, $L_e = 0.4$ μ m

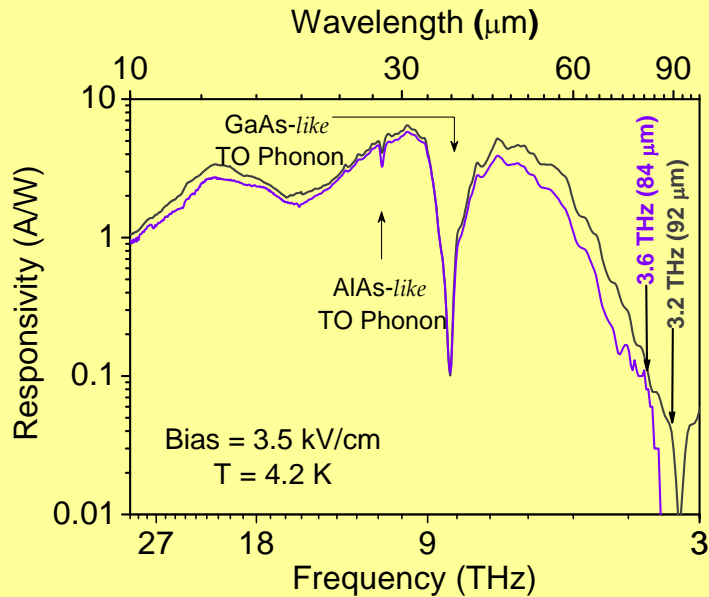


Higher energy electrons (> 8 THz) undergo a phonon emission giving a lower photoemission efficiency (> 8 THz)

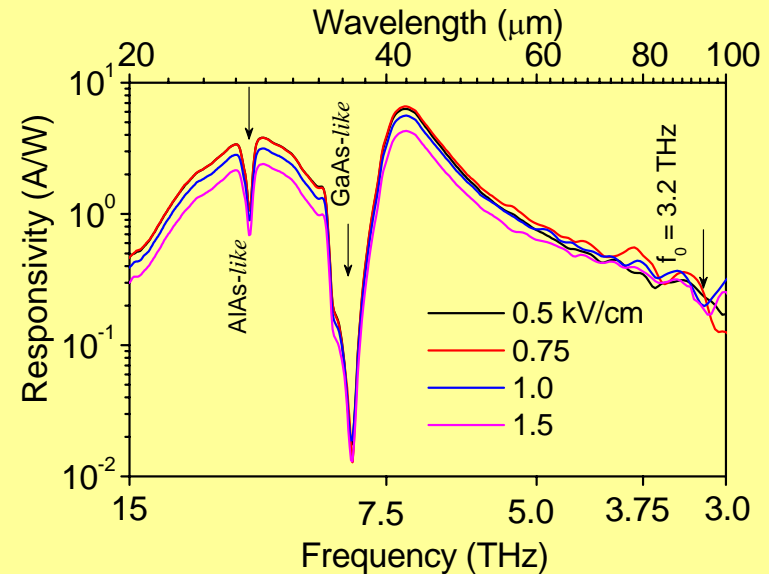
1. J. M. Mooney and J. Silverman, IEEE Trans. Electron. Devices, **33**, (1985)

- Threshold frequency - 3.2 THz ($92 \mu\text{m}$)¹, Al fraction used – 0.005
- $R_{\text{peak}} = 6.0 \text{ A/W}$ at 10 THz ($30 \mu\text{m}$).

p - type



n - type with doped substrate



	p-type	n-type
f_0 (THz)	3.2	3.2
R_{peak} (A/W)	6.0	6.4
Al fraction	0.005	0.04

1. Matsik et.at., *Appl. Phys. Lett.*, 82, (2003)

- n-type HEIWIP terahertz detector with 3.2 THz (93 μm) threshold frequency has been successfully demonstrated.
- Al fraction used in the barrier is 0.04. Therefore, threshold frequency smaller than 3 THz can be achieved easily while keeping doping concentration in the emitter low ($\sim 1\text{E}18 \text{ cm}^{-3}$)
- $R_{\text{peak}} = 6.4 \text{ A/W}$ at 7.1 THz (30 μm) was obtained at 0.7 kV/cm.
- It may be possible to go below 3 THz with n-type HEIWIP